## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination	
10645352	RYPAN, ZENON	
Examiner	Art Unit	
Philip H Leung	3742	

SEARCHED						
Class	Subclass	Date	Examiner			
219	756-757, 745-746, 754, 680	updated	P.L.			
312	236	2-18-2008				
126	37R					
D7	351					

SEARCH NOTES				
Search Notes	Date	Examiner		

INTERFERENCE SEARCH					
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